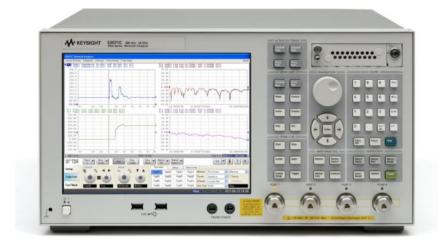
## MIPI Tx/Rx Interface S-parameter & Impedance Measurements with ENA Option TDR

Component Test Division - Kobe

October 2014





### Purpose

 This slide will show how to make measurements of MIPI Tx/Rx Interface S-parameter & Impedance Measurements Conformance Tests by using the Keysight E5071C ENA Option TDR.



## Keysight Digital Standards Program

Our solutions are driven and supported by Keysight experts involved in international standards committees:

- Joint Electronic Devices Engineering Council (JEDEC)
- PCI Special Interest Group (PCI-SIG®)
- Video Electronics Standards Association (VESA)
- Serial ATA International Organization (SATA-IO)
- High-Definition Multimedia Interface (HDMI)
- USB-Implementers Forum (USB-IF)
- Mobile Industry Processor Interface (MIPI) Alliance
- Optical Internetworking Forum (OIF)
- Mobile High-Definition Link (MHL) Consortium

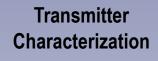
We're active in standards meetings, workshops, plugfests, and seminars

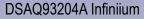
Our customers test with highest confidence and achieve compliance faster





## Keysight MIPI D-PHY and M-PHY Solution Coverage







U7238A D-PHY app U7249A M-PHY app

InfiniiMax Probes

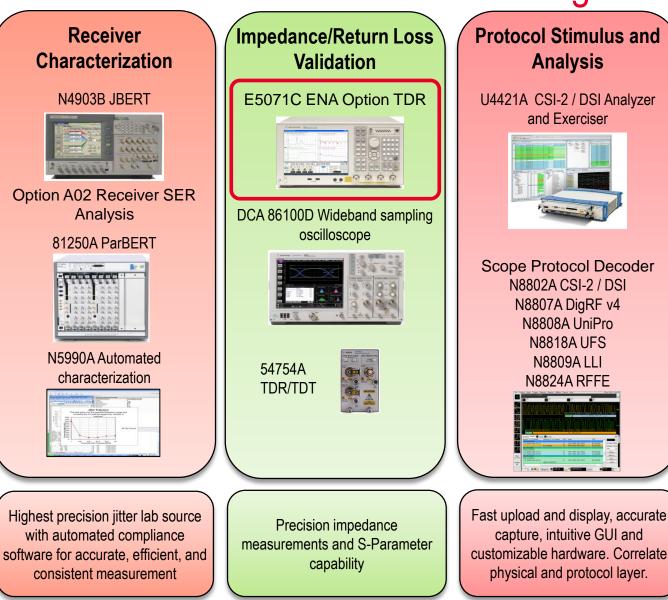


N2809A PrecisionProbe

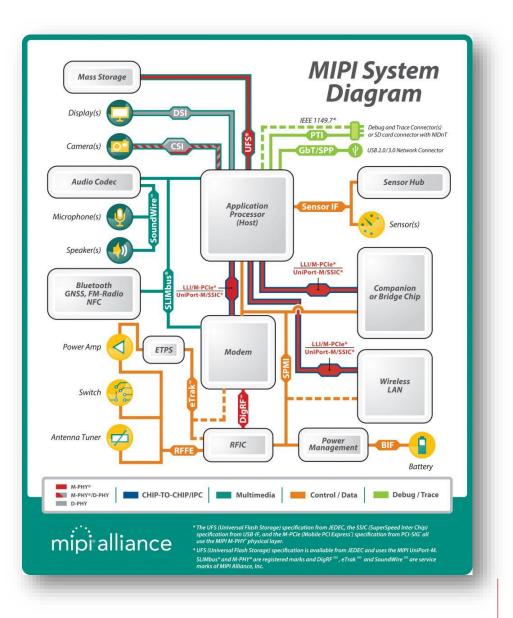


Industry's highest analog bandwidth, lowest noise floor/sensitivity, jitter measurement floor with unique cable/probe correction



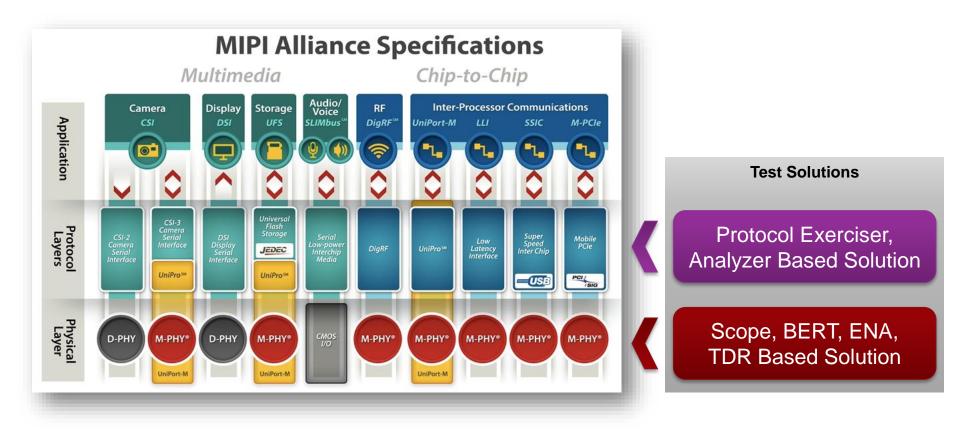


### **MIPI Interfaces in a Mobile Platform**



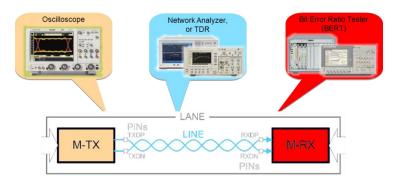


## **MIPI Alliance Specifications and Test Solutions**





## PHY Conformance Test Suite(CTS) Requirements



Three test sections outlined in the CTS are:

- TX Timers and Signaling
  - Voltage, Eye-opening, Jitter, Rise/Fall time, Skew, Slew rate, etc
- RX Timers and Electrical Tolerances
  - Amplitude, Jitter, Termination, Skew tolerance, etc
- Interface S-parameters and Impedance
  - Return loss, impedance mismatch, etc



### References

- MIPI Alliance Specification for M-PHY v3.0
- MIPI Alliance Conformance Test Suite for M-PHY Physical Layer v1.0

- MIPI Alliance Specification for D-PHY v1.1
- MIPI Alliance Conformance Test Suite for D-PHY Physical Layer v1.1 r03



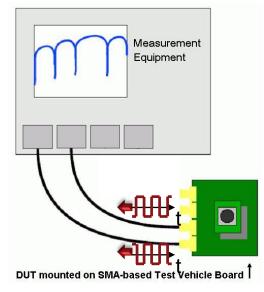
## Measurements for M-PHY

### ♦S-parameter Measurements

	Тх	Rx
Differential Return Loss	$\checkmark$	$\checkmark$
Common-mode Return Loss	$\checkmark$	-

#### Impedance Measurements

	Тх	Rx
Single-Ended Output Resistance (DIF-N/DIF-P and Stall/Sleep state)	$\checkmark$	-
Single-Ended Output Resistance Mismatch	$\checkmark$	-
Differential Termination Resistance	-	$\checkmark$

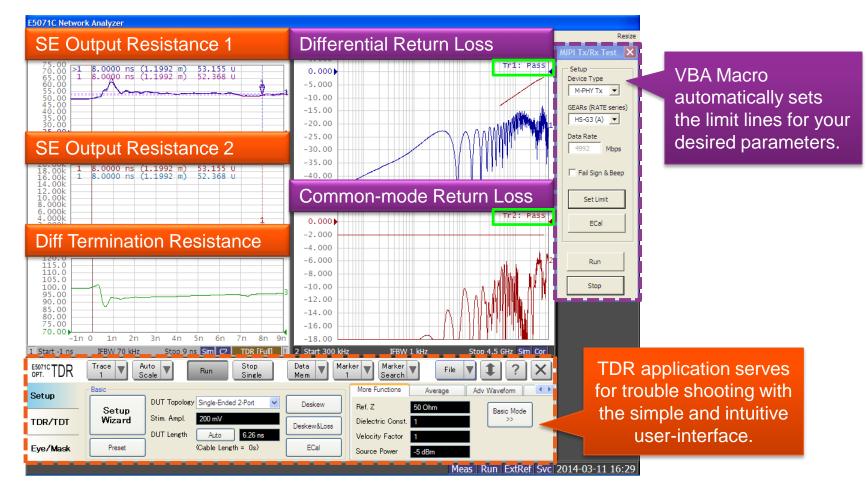


Power on and configure the DUT to force its M-TX into a continuously transmitting HS state, transmitting a continuous CRPAT repeating pattern.



## Example Using ENA Option TDR

### ♦All Measurements in One Screen





### Measurements for D-PHY

#### ♦S-parameter Measurements

	Тх	Rx
Differential Return Loss	$\checkmark$	$\checkmark$
Common-mode Return Loss	$\checkmark$	$\checkmark$
CMN-Diff Mode Conversion	$\checkmark$	$\checkmark$

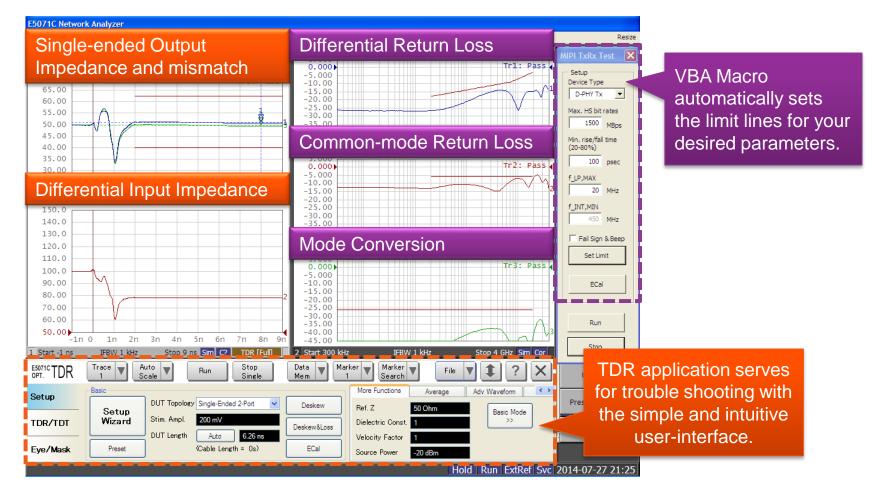
#### ◆Impedance Measurements

	Тх	Rx
Single-Ended Output Impedance	$\checkmark$	-
Single-Ended Output Impedance Mismatch	$\checkmark$	-
Differential Input Impedance	-	$\checkmark$



## Example Using ENA Option TDR

### ♦All Measurements in One Screen





## MOIs & State Files are available from A.com

#### www.keysight.com/find/ena-tdr\_compliance

		MOIs &	State Files	
	Standards	Cable-Connector Assembly	Tx/Rx Impedance	Test Solution Overview
USB	USB2.0	Coming soon	Coming soon	Coming soon
	USB3.0	Available	-	Available
	USB3.1	Coming soon	-	Coming soon
DMI	HDMI 1.4b	Available	-	Available
	HDMI 2.0	(*2)	Available	Coming soon
5ATA		Available	Available	Available
DisplayPor	t	Available	-	Available
VIPI™	D-PHY	-	Available	Available
	M-PHY	-	Available	Available
hernet:	100BASE-TX	Available	-	
	10GBASE-T	Available	-	Available
	10GBASE-KR / 40GBASE-KR4	Available (*3)	Available	
ИНL		Available	Coming soon	Download MOIs and test packages
PCIe®		Available	-	
hunderbo	olt 🖗	-	Available (*1)	Documents & Downloads
	ach 🖗	Available (*1)	-	Agilent Method of Implementation (MOI) for MIPI M-PHY Conformance Tests 🖉
BroadR-Re				
BroadR-Re SD Card 邼	UHS-II	-	Available (*1)	Agilent Method of Implementation (MOI) for MIPI M-PHY Conformance Tests Using Agilent E5071C ENA Network Analyzer Option TDR Application Note 201

Programming Example

\*1: Contact Keysight sales representative for more detail.

\*2: HDMI 2.0 uses the same cable as HDMI 1.4b.

\*3: Backplane interconnect tests

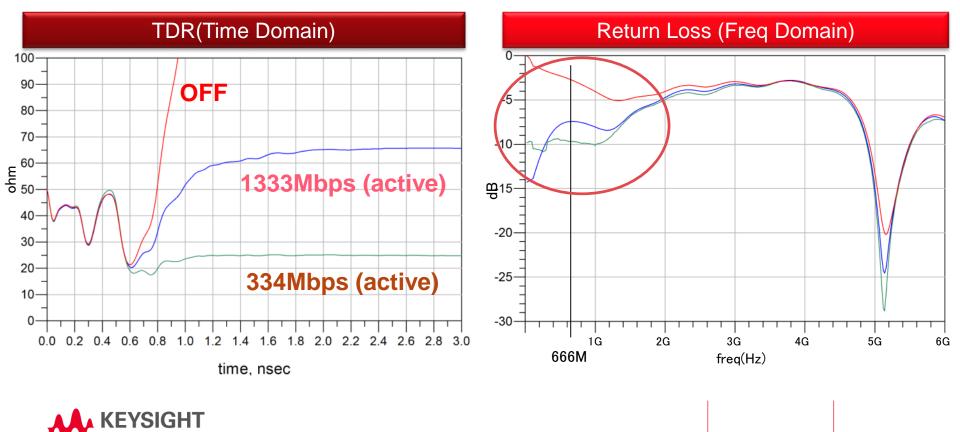


2011-12-01

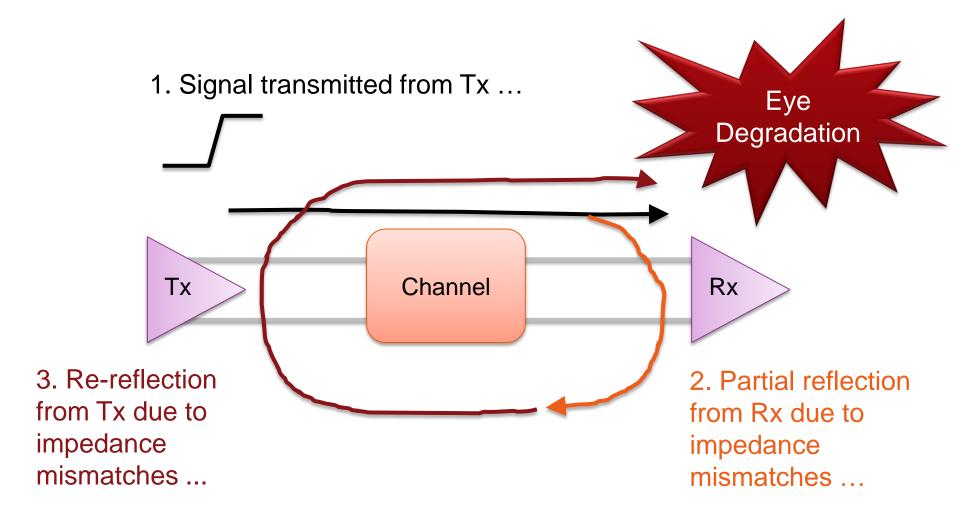
## Hot TDR Measurements - Why Measure?

•Hot TDR measurement is the impedance analysis of active devices under actual operation conditions.

•Typically, impedance of the device in the OFF state and ON state (Hot TDR) is significantly different. Impedance may vary with the data rate as well.



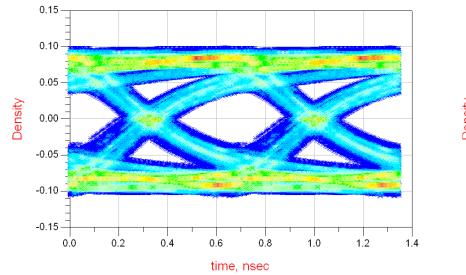
### Hot TDR Measurements - Why Measure?



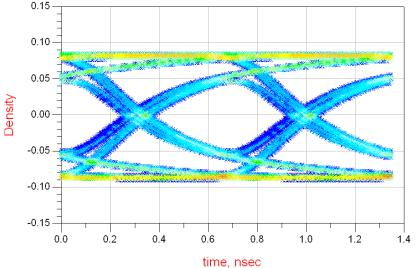


## Hot TDR Measurements - Why Measure?

### **Source Termination Effects**



Source Impedance **NOT** Matched



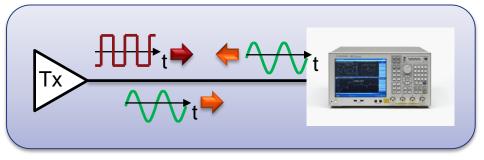
#### Source Impedance Matched



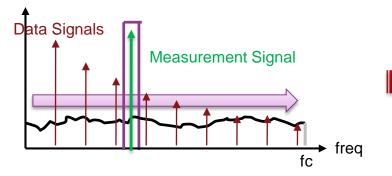
## Advantages of VNA Based Solution

Fast and Accurate Measurements

Since the measurements must be performed while the device is turned on, data signals from the transmitter cause measurement error. ENA can resolve this trouble in a smart way.

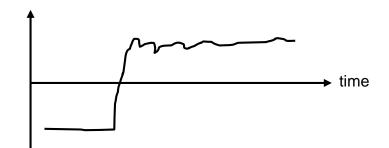


Narrowband receiver minimizes the effects of the data signal from the transmitter



ENA sweeps across desired frequency range. The spurious frequencies can be avoided during the sweep.

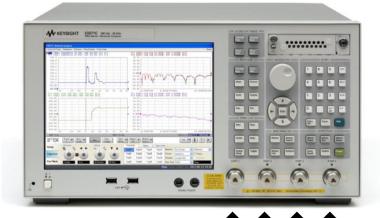
S-parameter can be converted into TDR.



Averaging is not necessary to obtain a stable waveform.



### Advantages of VNA Based Solution ESD Robustness

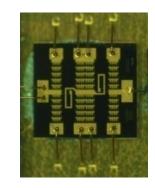




### ENA has ESD protection circuits inside

**ESD** Survival:

IEC 801-2 Human Body Model. (150 pF, 330  $\Omega$ ) RF Output Center pins tested to 3,000 V, 10 cycles

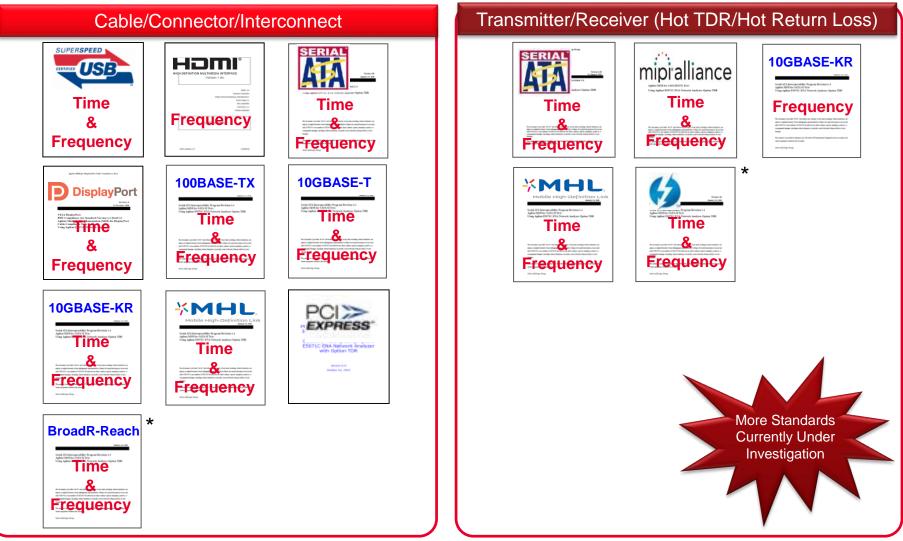


Proprietary ESD protection chip significantly increase ESD robustness, while at the same time maintaining **excellent RF performance** (22ps rise time for 20GHz models).



## **ENA Option TDR Compliance Test Solution**

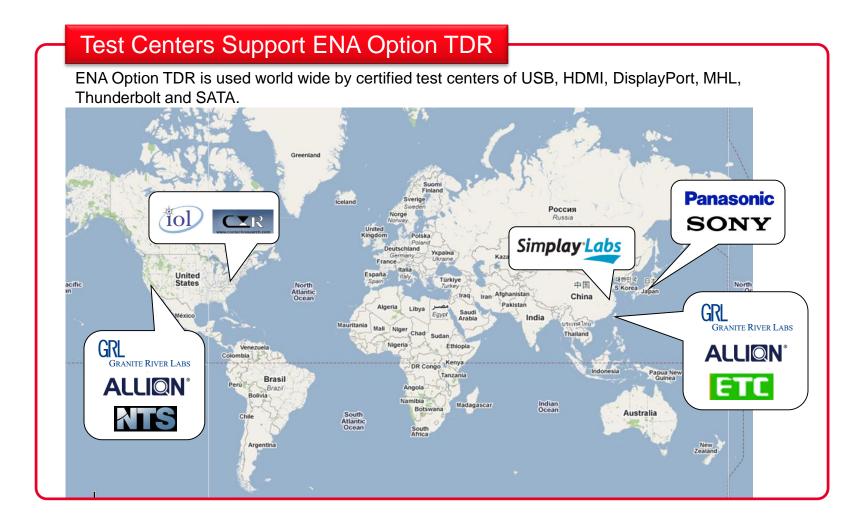
Certified MOIs available at www.keysight.com/find/ena-tdr\_compliance



\* For more detail about Thunderbolt and BroadR-Reach compliance test solution using the ENA Option TDR, contact Keysight sales representative.



### ENA Option TDR Compliance Test Solution Certified Test Centers using ENA Option TDR







# **Questions?**





## **Keysight VNA Solutions**



**PNA-X, NVNA** Industry-leading performance 10 M to 13.5/26.5/43.5/50/67 GHz Banded mm-wave to 2 THz

### PNA



Performance VNA 10 M to 20, 40, 50, 67, 110 GHz Banded mm-wave to 2 THz

PNA-L

World's most capable value VNA 300 kHz to 6, 13.5, 20 GHz 10 MHz to 40, 50 GHz





PNA-X receiver 8530A replacement Mm-wave solutions Up to 2 THz

**PNA Series** 

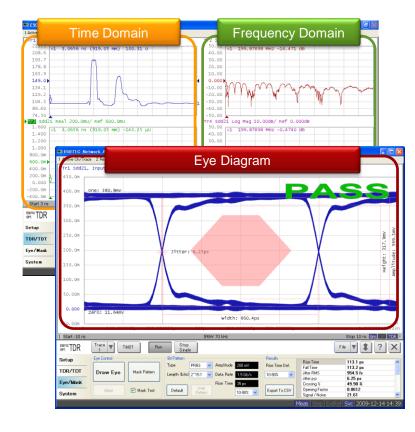
Performance **E5072A** Best performance **ENA** 30 kHz o 4.5, 8.5 E5071C GHz World's most popular economy VNA 9 kHz to 4.5, 8.5 GHz E5061B 300 kHz to 20.0 GHz NA + ZA in one-bex FieldFox 5 Hz to 3 GHz Low cost RF VNA Handheld RF **ENA Series** 100 k to 1.5/3.0 GHz Analyzer 5 Hz to 4/6 GHz



## What is ENA Option TDR?

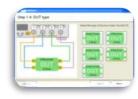


The ENA Option TDR is an application software embedded on the ENA, which provides an **one-box solution** for high speed serial interconnect analysis.



### **3 Breakthroughs**

for Signal Integrity Design and Verification

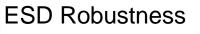


Simple and Intuitive Operation



Fast and Accurate Measurements







## What is ENA Option TDR?

### [Video] *Keysight ENA Option TDR Change the world of Time Domain Reflectometry (TDR) Measurements*

- youtu.be/uBHXkzk4lzk?list=PLG98L-F0jgVj-jeYUheKdpGhr5z1Jg4q\_
- www.keysight.com/find/ena-tdr





### **Additional Resources**

### •ENA Option TDR Reference Material

www.keysight.com/find/ena-tdr

- •Technical Overview (5990-5237EN)
- Application Notes

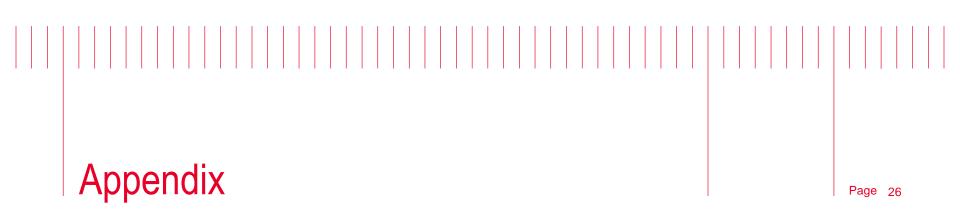


- •Correlation between TDR oscilloscope and VNA generated time domain waveform (5990-5238EN)
- •Comparison of Measurement Performance between Vector Network Analyzer and TDR Oscilloscope (5990-5446EN)
- •Effective Hot TDR Measurements of Active Devices Using ENA Option TDR (5990-9676EN)
- •Measurement Uncertainty of VNA Based TDR/TDT Measurement (5990-8406EN)
- •Accuracy Verification of Agilent's ENA Option TDR Time Domain Measurement using a NIST Traceable Standard (5990-5728EN)

### •Method of Implementation (MOI) for High Speed Digital Standards

www.keysight.com/find/ena-tdr\_compliance



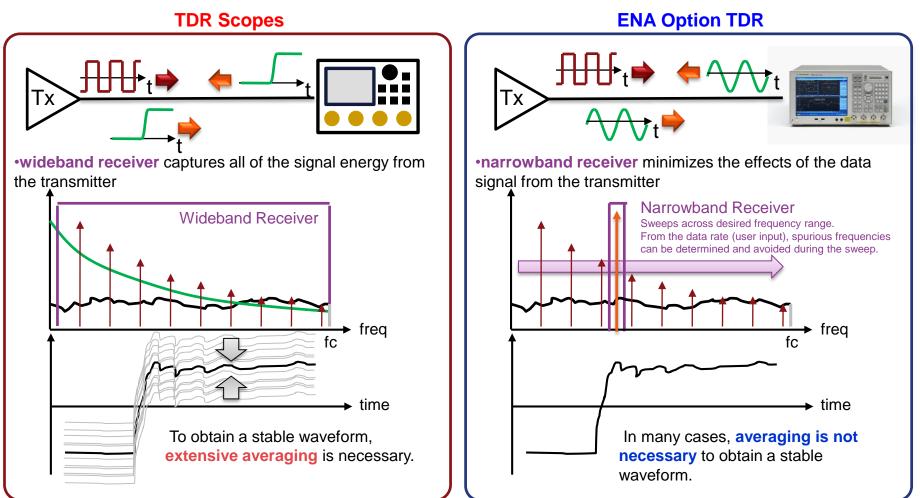




# Advantages of ENA Option TDR

Fast and Accurate Measurements

For Hot TDR measurements, data signals from the transmitter cause measurement error...





### Advantages of ENA Option TDR ESD Robustness

#### TDR scopes are sensitive to ESD. Test Por Thru-Line Terminated CAUTION Sampler Step Generator STATIC SENSITIVE CONNECTORS Test Port USE ESD Protection PROTECTION Circuit Thru-Line Terminated Sampler Step Generator

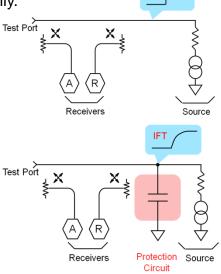
**TDR Scopes** 

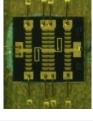
Implementing a protection circuit is difficult, because it will slow down the rise time of the step stimulus.

#### **ENA Option TDR**

ENA Option TDR has higher robustness against ESD, because protection circuits can be implement more easily.

ENA Option TDR measures the vector ratios of the transmitted and received signals. Therefore, the effects of the protection circuit will be canceled out.





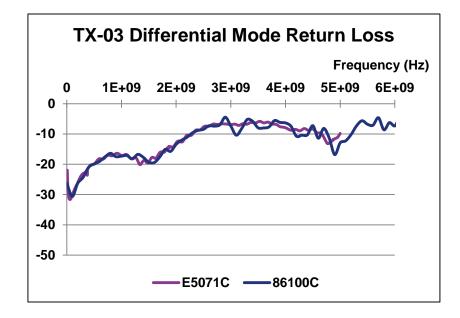
Proprietary ESD protection chip significantly increase ESD robustness, while at the same time maintaining **excellent RF performance** (22ps rise time for 20GHz models).

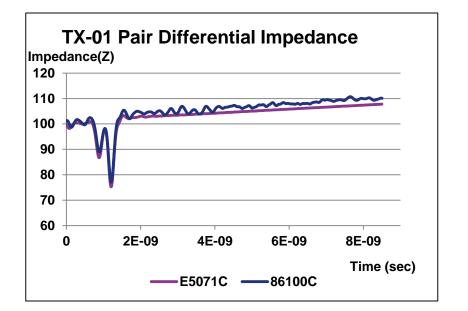


# Advantages of ENA Option TDR

Fast and Accurate Measurements

Correlation between 86100C TDR oscilloscope and E5071C ENA Option TDR



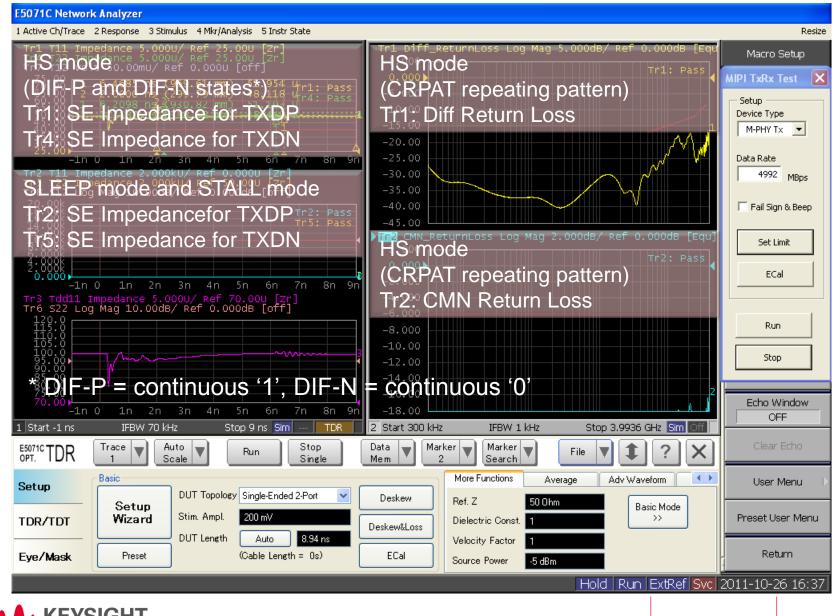




Time (sec)

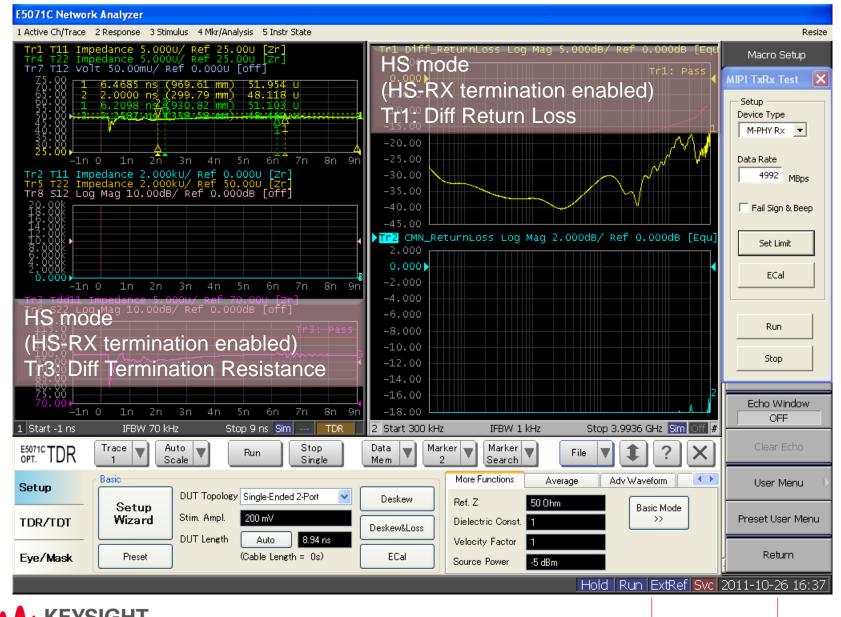
## **M-PHY Tx Device**

CHNOLOGI



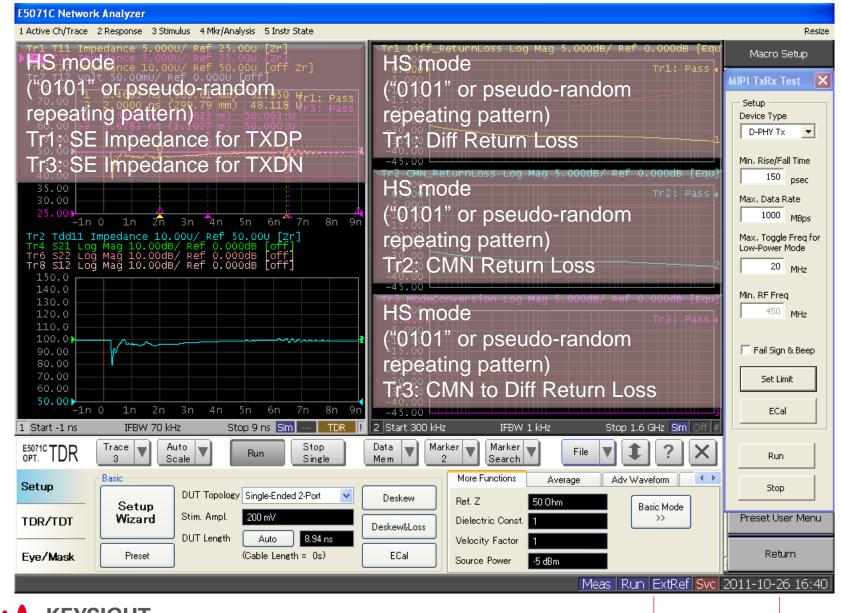
### **M-PHY Rx Device**

ECHNOLOGI



## **D-PHY Tx Device**

CHNOLOGI



### **D-PHY Rx Device**

ECHNOLOGI

